



## FDH45N50F

500V N-Channel MOSFET, FRFET

### Features

- 45A, 500V,  $R_{DS(on)} = 0.12\Omega$  @  $V_{GS} = 10\text{ V}$
- Low gate charge ( typical 105 nC)
- Low  $C_{rss}$  ( typical 62 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

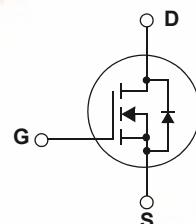
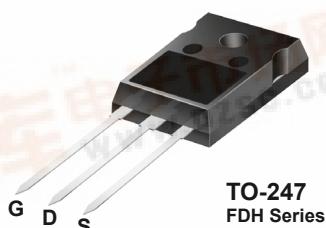
January 2006

**UniFET™**

### Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.

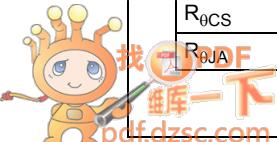


### Absolute Maximum Ratings

Symbol	Parameter	FDH45N50F	Unit
$V_{DSS}$	Drain-Source Voltage	500	V
$I_D$	Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ ) - Continuous ( $T_C = 100^\circ\text{C}$ )	45 28.4	A A
$I_{DM}$	Drain Current - Pulsed	(Note 1)	A
$V_{GSS}$	Gate-Source voltage	$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy	(Note 2)	mJ
$I_{AR}$	Avalanche Current	(Note 1)	A
$E_{AR}$	Repetitive Avalanche Energy	(Note 1)	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$	(Note 3)	V/ns
$P_D$	Power Dissipation ( $T_C = 25^\circ\text{C}$ ) - Derate above $25^\circ\text{C}$	625 5	W W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300	$^\circ\text{C}$

### Thermal Characteristics

Symbol	Parameter	Min.	Max.	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	--	0.2	$^\circ\text{C/W}$
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24	--	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	--	40	$^\circ\text{C/W}$



## Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDH45N50F	FDH45N50F	TO-247	-	-	30

## Electrical Characteristics

$T_C = 25^\circ\text{C}$  unless otherwise noted

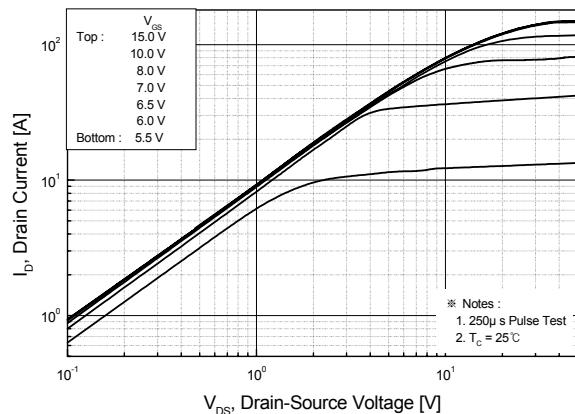
Symbol	Parameter	Conditions	Min.	Typ.	Max	Units
<b>Off Characteristics</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}} = 0\text{V}$ , $I_D = 250\mu\text{A}$	500	--	--	V
$\Delta \text{BV}_{\text{DSS}} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	0.5	--	$^\circ\text{C}$
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 500\text{V}$ , $V_{\text{GS}} = 0\text{V}$ $V_{\text{DS}} = 400\text{V}$ , $T_C = 125^\circ\text{C}$	--	--	25 250	$\mu\text{A}$ $\mu\text{A}$
$I_{\text{GSSF}}$	Gate-Body Leakage Current, Forward	$V_{\text{GS}} = 30\text{V}$ , $V_{\text{DS}} = 0\text{V}$	--	--	100	nA
$I_{\text{GSSR}}$	Gate-Body Leakage Current, Reverse	$V_{\text{GS}} = -30\text{V}$ , $V_{\text{DS}} = 0\text{V}$	--	--	-100	nA
<b>On Characteristics</b>						
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}$ , $I_D = 250\mu\text{A}$	3.0	--	5.0	V
$R_{\text{DS(on)}}$	Static Drain-Source On-Resistance	$V_{\text{GS}} = 10\text{V}$ , $I_D = 22.5\text{A}$	--	0.105	0.12	$\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{\text{DS}} = 40\text{V}$ , $I_D = 22.5\text{A}$	(Note 4)	--	49.0	--
<b>Dynamic Characteristics</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{\text{DS}} = 25\text{V}$ , $V_{\text{GS}} = 0\text{V}$ , $f = 1.0\text{MHz}$	--	5100	6630	pF
$C_{\text{oss}}$	Output Capacitance		--	790	1030	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance		--	62	--	pF
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}} = 400\text{V}$ , $V_{\text{GS}} = 0\text{V}$ , $f = 1.0\text{MHz}$	--	161	--	pF
$C_{\text{oss eff.}}$	Effective Output Capacitance	$V_{\text{DS}} = 0\text{V}$ to $400\text{V}$ , $V_{\text{GS}} = 0\text{V}$	--	342	--	pF
<b>Switching Characteristics</b>						
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}} = 250\text{V}$ , $I_D = 48\text{A}$ $R_G = 25\Omega$	--	140	290	ns
$t_r$	Turn-On Rise Time		--	500	1010	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time		--	215	440	ns
$t_f$	Turn-Off Fall Time		--	245	500	ns
$Q_g$	Total Gate Charge	$V_{\text{DS}} = 400\text{V}$ , $I_D = 48\text{A}$ $V_{\text{GS}} = 10\text{V}$	--	105	137	nC
$Q_{\text{gs}}$	Gate-Source Charge		--	33	--	nC
$Q_{\text{gd}}$	Gate-Drain Charge		--	45	--	nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_S$	Maximum Continuous Drain-Source Diode Forward Current	--	--	45	--	A
$I_{\text{SM}}$	Maximum Pulsed Drain-Source Diode Forward Current	--	--	180	--	A
$V_{\text{SD}}$	Drain-Source Diode Forward Voltage	$V_{\text{GS}} = 0\text{V}$ , $I_S = 45\text{A}$	--	--	1.4	V
$t_{\text{rr}}$	Reverse Recovery Time	$V_{\text{GS}} = 0\text{V}$ , $I_S = 45\text{A}$ $dI_F/dt = 100\text{A}/\mu\text{s}$	--	188	--	ns
$Q_{\text{rr}}$	Reverse Recovery Charge		(Note 4)	--	0.64	$\mu\text{C}$

### NOTES:

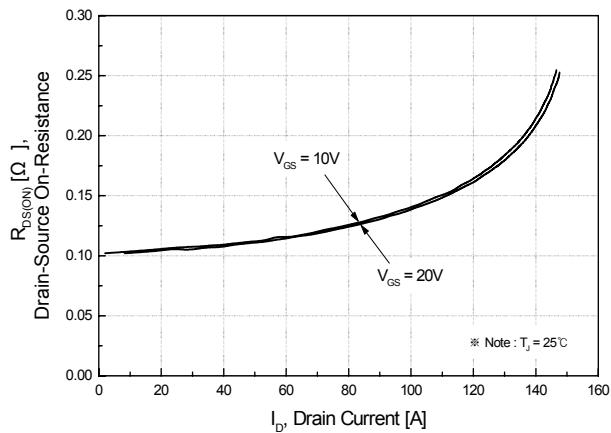
1. Repetitive Rating: Pulse width limited by maximum junction temperature
2.  $L = 1.46\text{mH}$ ,  $I_{AS} = 48\text{A}$ ,  $V_{DD} = 50\text{V}$ ,  $R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq 45\text{A}$ ,  $dI/dt \leq 200\text{A}/\mu\text{s}$ ,  $V_{DD} \leq \text{BV}_{\text{DSS}}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$
5. Essentially Independent of Operating Temperature Typical Characteristics

## Typical Performance Characteristics

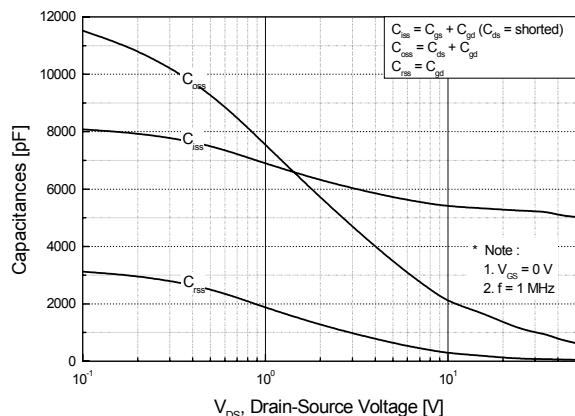
**Figure 1. On-Region Characteristics**



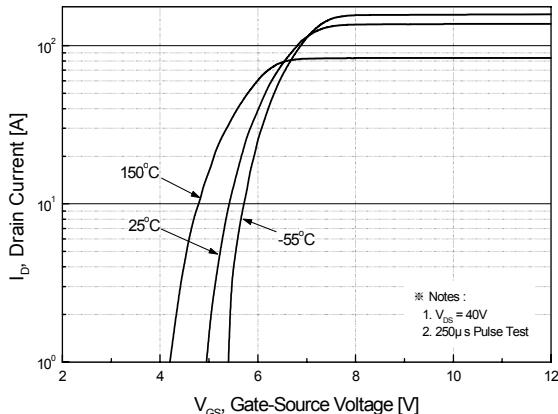
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



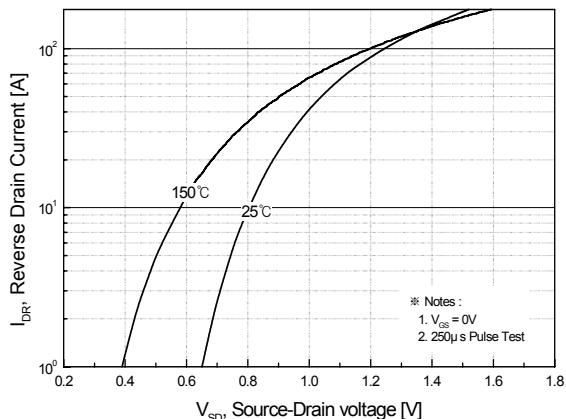
**Figure 5. Capacitance Characteristics**



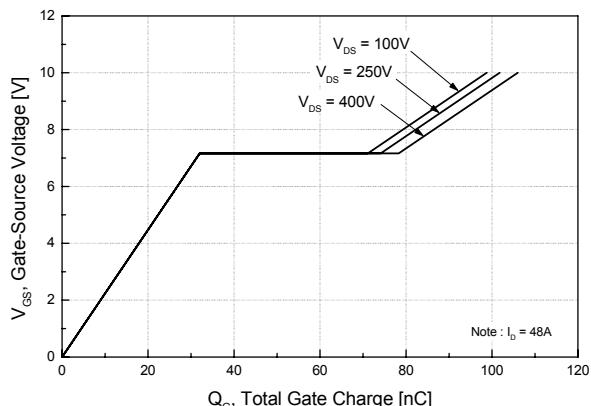
**Figure 2. Transfer Characteristics**



**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**

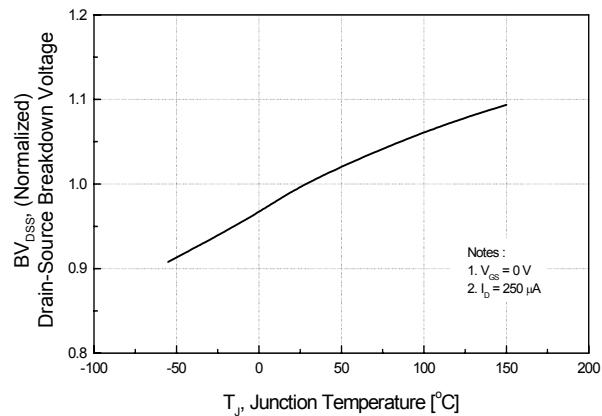


**Figure 6. Gate Charge Characteristics**

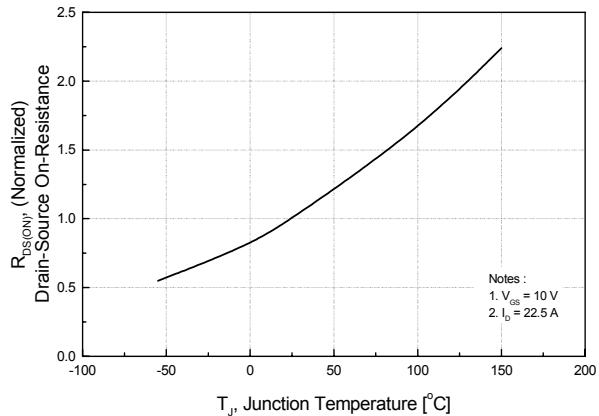


## Typical Performance Characteristics (Continued)

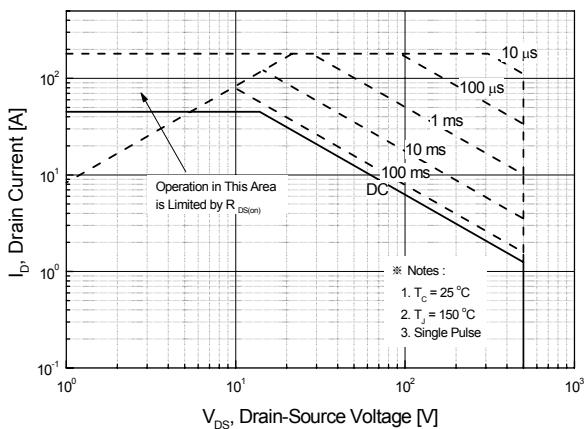
**Figure 7. Breakdown Voltage Variation vs. Temperature**



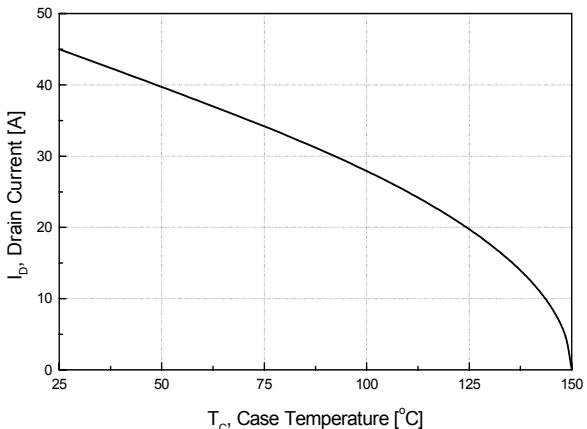
**Figure 8. On-Resistance Variation vs. Temperature**



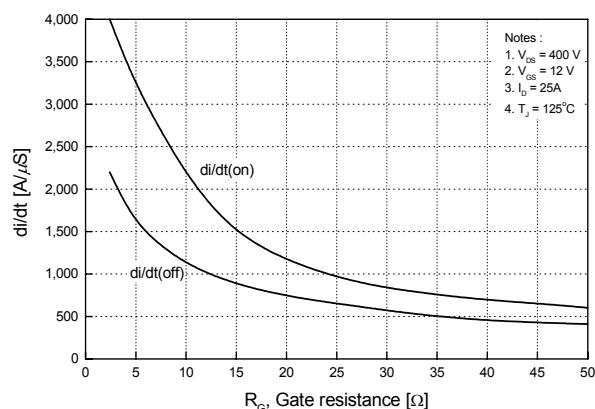
**Figure 9. Maximum Safe Operating Area**



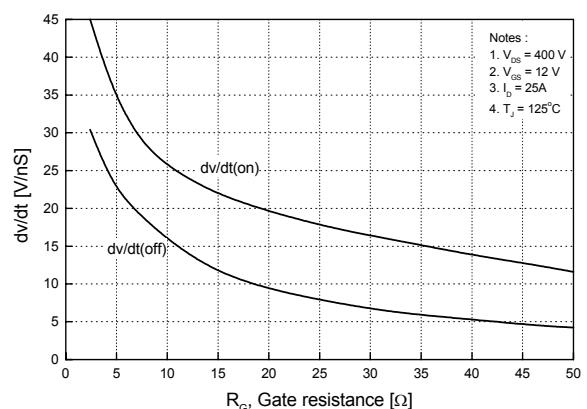
**Figure 10. Maximum Drain Current vs. Case Temperature**



**Figure 11. Typical Drain Current Slope vs. Gate Resistance**

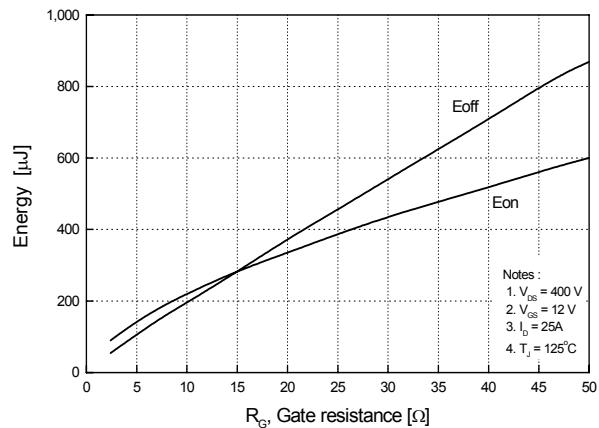


**Figure 12. Typical Drain-Source Voltage Slope vs. Gate Resistance**

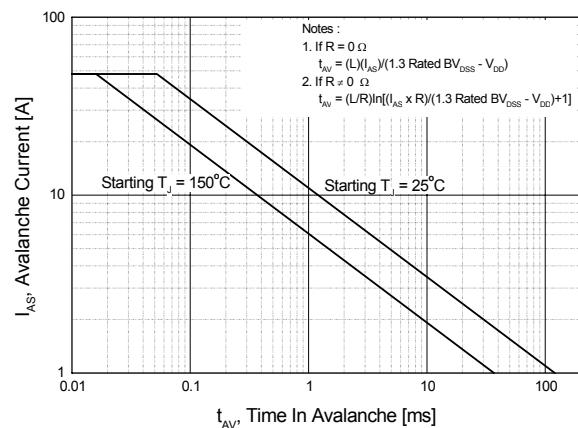


## Typical Performance Characteristics (Continued)

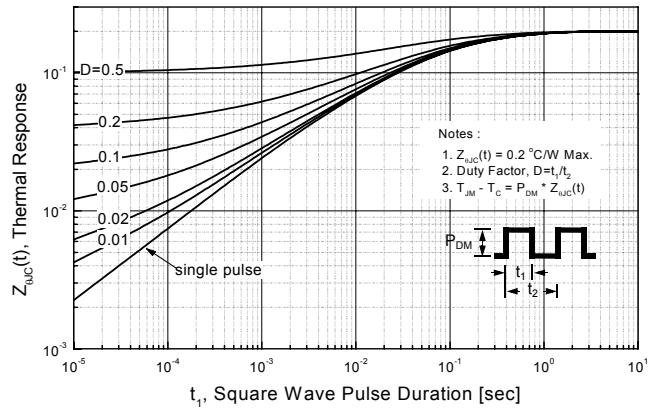
**Figure 13. Typical Switching Losses vs. Gate Resistance**



**Figure 14. Unclamped Inductive Switching Capability**

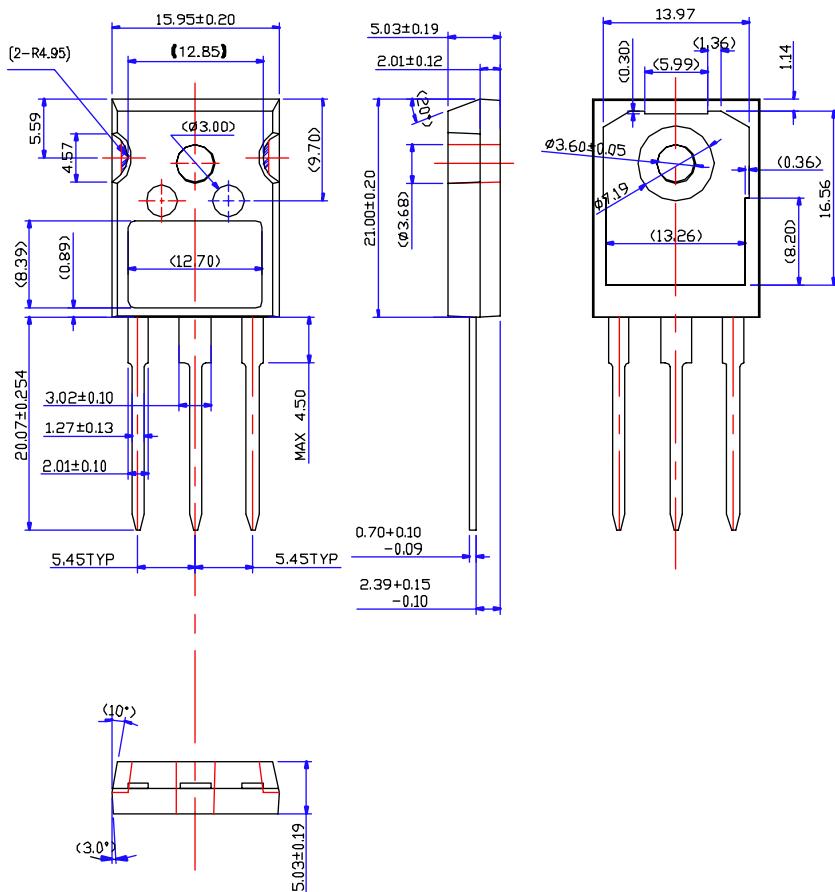


**Figure 15. Transient Thermal Resistance Curve**



## Mechanical Dimensions

**TO-247AD (FKS PKG CODE 001)**



Dimensions in Millimeters

## TRADEMARKS

ACEx™	FAST®	ISOPLANAR™	PowerSaver™	SuperSOT™-6
ActiveArray™	FASTR™	LittleFET™	PowerTrench®	SuperSOT™-8
Bottomless™	FPS™	MICROCOUPLER™	QFET®	SyncFET™
Build it Now™	FRFET™	MicroFET™	QS™	TinyLogic®
CoolFET™	GlobalOptoisolator™	MicroPak™	QT Optoelectronics™	TINYOPTO™
CROSSVOLT™	GTO™	MICROWIRE™	Quiet Series™	TruTranslation™
DOME™	HiSeC™	MSX™	RapidConfigure™	UHC™
EcoSPARK™	I <sup>2</sup> C™	MSXPro™	RapidConnect™	UltraFET®
E <sup>2</sup> CMOS™	i-Lo™	OCX™	μSerDes™	UniFET™
EnSigna™	ImpliedDisconnect™	OCXPro™	ScalarPump™	VCX™
FACT™	IntelliMAX™	OPTOLOGIC®	SILENT SWITCHER®	Wire™
FACT Quiet Series™		OPTOPLANAR™	SMART START™	
		PACMAN™	SPM™	
Across the board. Around the world.™		POP™	Stealth™	
The Power Franchise®		Power247™	SuperFET™	
Programmable Active Droop™		PowerEdge™	SuperSOT™-3	

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## PRODUCT STATUS DEFINITIONS

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